

**Functional level test set generation methods**

**Ubar, Raimund-Johannes** Proceedings of the 12th Conference on Fault-Tolerant Systems and Diagnostics, Prague, Czechoslovakia, September, 1989 1989 / p. 46-55

**Multivalued simulation on AG-model of digital devices**

**Ubar, Raimund-Johannes; Voolaine, Andrus** Proceedings of the 12th Conference on Fault-Tolerant Systems and Diagnostics, Prague, Czechoslovakia, September, 1989 1989 / p. 101-104